

CLAIMS

What is claimed is:

1. An evaluator board comprising:

an electrical connection receptacle mounted on the evaluator board;

a connection base mounted on the evaluator board, the connection base being configured to receive an upper surface of a subcomponent;

one or more electrical points extending from the exposed surface of the connection base, the one or more electrical points providing a communicable electrical connection between the upper surface of the subcomponent and the one or more circuit traces; and

a securing mechanism positioned substantially over the connection base.

2. The evaluator board as recited in claim 1, wherein the subcomponent is at least one of a printed circuit board for use in an optical transceiver, a module interface board, and a test coupon board.

3. The evaluator board as recited in claim 1, wherein the connection base is positioned opposite the electrical connection receptacle such that the subcomponent is connected to the connection base and electrical connection receptacle at two opposing ends.

4. The evaluator board as recited in claim 1, wherein the electrical connection receptacle is configured to receive an edge connector portion of the subcomponent.

5. The evaluator board as recited in claim 1, wherein the evaluator board comprises circuitry components on both an upper and lower surface of the evaluator board, wherein the circuitry are communicably connected for testing the subcomponent.

6. The evaluator board as recited in claim 1, further comprising one or more stoppers extending from the evaluator board, the one or more stoppers positioned such that the subcomponent is received into the electrical connection receptacle while maintaining electrical conductivity.

7. The evaluator board as recited in claim 1, further comprising one or more guideposts extending from the connection base, the one or more guideposts configured to secure the subcomponent in an appropriate alignment with respect to the connection base.

8. The evaluator board as recited in claim 1, wherein the securing mechanism comprises a clamp having a depressible arm and a retractable clamp head.

9. The evaluator board as recited in claim 1, further comprising one or more connection ports for connecting the evaluator board to a computerized system.

10. The evaluator board as recited in claim 9, wherein the one or more connection ports include at least one of a serial port, a parallel port, a small computer system interface port, a USB port, an Ethernet port, and an optical connection port.

11. An evaluator board for testing one or more subcomponents of a printed circuit board assembly comprising:

a printed circuit board;

one or more circuitry components for performing one of driving and testing a subcomponent to be tested, the one or more circuitry components mounted on both an upper surface and a lower surface of the printed circuit board;

one or more receiving components configured to receive the subcomponent to be tested, at least one of the receiving components communicably connected to at least one of the one or more evaluator components.

12. The evaluator board as recited in claim 11, wherein at least one of the one or more receiving components is configured to receive an edge connector of the subcomponent to be tested.

13. The evaluator board as recited in claim 11, wherein the printed circuit board comprises one or more perforations that allow one or more circuit lines to transfer data between evaluator components on the upper surface and the lower surface of the printed circuit board.

14. The evaluator board as recited in claim 11, further comprising one or more stoppers extending from the printed circuit board, the one or more stoppers configured to position the subcomponent adjacent one or more of the one or more receiving components.

15. The evaluator board as recited in claim 11, further comprising one or more guideposts extending from at least one of the one or more receiving components, the

one or more guideposts configured to fit within one or more corresponding perforations in the subcomponent.

16. The evaluator board as recited in claim 11, further comprising one or more connection points extending from at least one of the one or more receiving components, the one or more connection points providing a communicable link between the subcomponent to be tested and an evaluator component mounted on one of the upper surface and lower surface of the printed circuit board.

17. The evaluator board as recited in claim 11, further comprising a retractable securing mechanism positioned over at least one of the one or more receiving components.

18. The evaluator board as recited in claim 11, further comprising one or more connection ports for connecting the evaluator board to a computerized system.

19. The evaluator board as recited in claim 18, wherein the one or more connection ports include at least one of a serial port, a parallel port, a small computer system interface port, a USB port, an Ethernet port, and an optical connection port.

20. A method of testing a subcomponent of a printed circuit board assembly comprising:

placing a subcomponent to be tested on a evaluator board such that an upper surface of the subcomponent fits against at least one of one or more receiving components mounted on the evaluator board;

positioning the subcomponent on the evaluator board so that a front end and a back end of the subcomponent are electrically connected to one or more components mounted on a lower surface and an upper surface of the evaluator board; and

clamping the subcomponent against the evaluator board, wherein a clamp secures the front end of the subcomponent to be tested against the connection base.

21. The method as recited in claim 20, wherein positioning the subcomponent to be tested comprises aligning one of the front end and the back end of the subcomponent to be tested into an edge connection receptacle.

22. The method as recited in claim 20, wherein positioning the subcomponent to be tested comprises sliding a notched portion of the subcomponent against one or more stoppers extending from the evaluator board.

23. The method as recited in claim 20, wherein positioning the subcomponent to be tested comprises sliding a receiving portion of the subcomponent to be tested onto a guidepost that extends from the evaluator board.